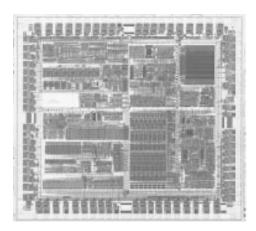


M80C186XL20, 16, 12, 10 16-BIT HIGH-INTEGRATION EMBEDDED PROCESSOR

- Low Power, Full Static Version of M80C186
- Operation Modes:
 - Enhanced Mode
 - DRAM Refresh Control Unit
 - Power-Save Mode
 - Direct Interface to 80C187
 - Compatible Mode
 - NMOS 80186 Pin-for-Pin
 Replacement for Non-Numerics
 Applications
- Integrated Feature Set
 - Static, Modular CPU
 - Clock Generator
 - 2 Independent DMA Channels
 - Programmable Interrupt Controller
 - 3 Programmable 16-Bit Timers
 - Dynamic RAM Refresh Control Unit
 - Programmable Memory and Peripheral Chip Select Logic
 - Programmable Wait State Generator
 - Local Bus Controller
 - Power-Save Mode
 - System-Level Testing Support (High Impedance Test Mode)

- Completely Object Code Compatible with Existing 8086/8088 Software and Has 10 Additional Instructions over 8086/8088
- Speed Versions Available
 - 20 MHz (M80C186XL20)
 - 16 MHz (M80C186XL16)
 - 12.5 MHz (M80C186XL12)
 - 10 MHz (M80C186XL)
- Direct Addressing Capability to 1 MByte Memory and 64 Kbyte I/O
- Complete System Development Support
 - All 8086 and 80C186 Software
 Development Tools Can Be Used for M80C186XL System Development
 - ASM 86 Assembler, PL/M-86,
 Pascal-86, Fortran-86, iC-86 and
 System Utilities
 - In-Circuit-Emulator (ICE™-186)
- Available in 68-Pin:
 - Ceramic Pin Grid Array (PGA)
- Military Temperature Range:
 - -55° C to $+125^{\circ}$ C (T_C)

The Intel M80C186XL is a Modular Core re-implementation of the M80C186 microprocessor. It offers higher speed and lower power consumption than the standard M80C186 but maintains 100% clock-for-clock functional compatibility. Packaging and pinout are also identical.



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M80C186XL20, 16, 12, 10 16-BIT HIGH INTEGRATION EMBEDDED PROCESSOR

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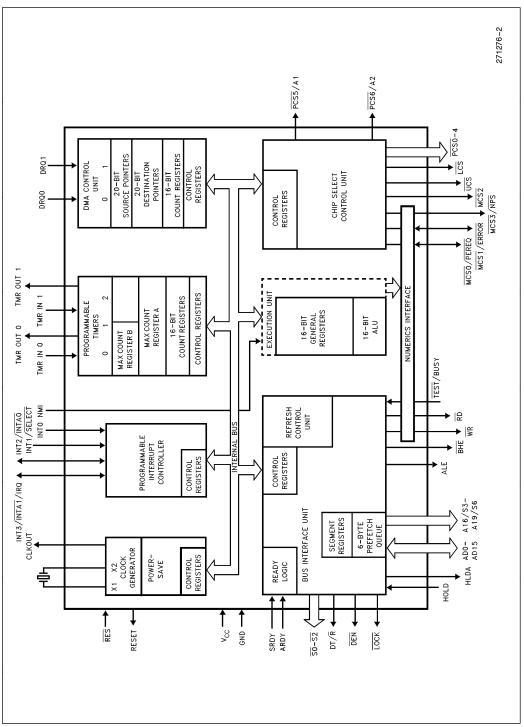


Figure 1. M80C186XL Block Diagram



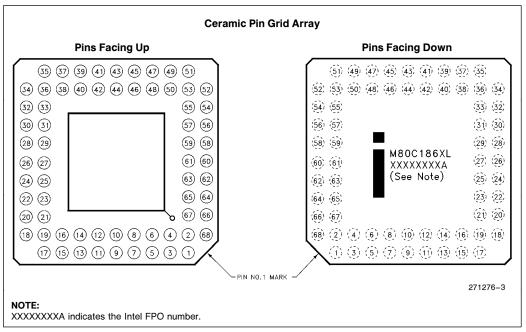


Figure 2. M80C186XL Pinout Diagrams



Table 1. M80C186XL Pin Description

Symbol	PGA Pin No.	Туре	Name and Function
V _{CC}	9 43	I	System Power: +5 volt power supply.
V _{SS}	26 60	I	System Ground.
RESET	57	0	RESET Output indicates that the M80C186XL CPU is being reset, and can be used as a system reset. It is active HIGH, synchronized with the processor clock, and lasts an integer number of clock periods corresponding to the length of the RES signal. Reset goes inactive 2 clockout periods after RES goes inactive. When tied to the TEST/BUSY pin, RESET forces the M80C186XL into enhanced mode. RESET is not floated during bus hold.
X1 X2	59 58	0	Crystal Inputs X1 and X2 provide external connections for a fundamental mode or third overtone parallel resonant crystal for the internal oscillator. X1 can connect to an external clock instead of a crystal. In this case, minimize the capacitance on X2. The input or oscillator frequency is internally divided by two to generate the clock signal (CLKOUT).
CLKOUT	56	0	Clock Output provides the system with a 50% duty cycle waveform. All device pin timings are specified relative to CLKOUT. CLKOUT is active during reset and bus hold.
RES	24	I	An active $\overline{\text{RES}}$ causes the M80C186XL to immediately terminate its present activity, clear the internal logic, and enter a dormant state. This signal may be asynchronous to the M80C186XL clock. The M80C186XL begins fetching instructions approximately $6\frac{1}{2}$ clock cycles after $\overline{\text{RES}}$ is returned HIGH. For proper initialization, V _{CC} must be within specifications and the clock signal must be stable for more than 4 clocks with $\overline{\text{RES}}$ held LOW. $\overline{\text{RES}}$ is internally synchronized. This input is provided with a Schmitt-trigger to facilitate power-on $\overline{\text{RES}}$ generation via an RC network.
TEST/BUSY	47	1/0	The TEST pin is sampled during and after reset to determine whether the M80C186XL is to enter Compatible or Enhanced Mode. Enhanced Mode requires TEST to be HIGH on the rising edge of RES and LOW four CLKOUT cycles later. Any other combination will place the M80C186XL in Compatible Mode. During power-up, active RES is required to configure TEST/BUSY as an input. A weak internal pullup ensures a HIGH state when the input is not externally driven. TEST—In Compatible Mode this pin is configured to operate as TEST. This pin is examined by the WAIT instruction. If the TEST input is HIGH when WAIT execution begins, instruction execution will suspend. TEST will be resampled every five clocks until it goes LOW, at which time execution will resume. If interrupts are enabled while the M80C186XL is waiting for TEST, interrupts will be serviced. BUSY—In Enhanced Mode, this pin is configured to operate as BUSY. The BUSY input is used to notify the M80C186XL of Math Coprocessor activity. Floating point instructions executing in the
			M80C186XL sample the BUSY pin to determine when the Math Coprocessor is ready to accept a new command. BUSY is active HIGH.



Table 1. M80C186XL Pin Description (Continued)

Symbol	PGA Pin No.	Туре	Name and Function
TMR IN 0 TMR IN 1	20 21	l I	Timer Inputs are used either as clock or control signals, depending upon the programmed timer mode. These inputs are active HIGH (or LOW-to-HIGH transitions are counted) and internally synchronized. Timer Inputs must be tied HIGH when not being used as clock or retrigger inputs.
TMR OUT 0 TMR OUT 1	22 23	0	Timer outputs are used to provide single pulse or continous waveform generation, depending upon the timer mode selected. These outputs are not floated during a bus hold.
DRQ0 DRQ1	18 19	l I	DMA Request is asserted HIGH by an external device when it is ready for DMA Channel 0 or 1 to perform a transfer. These signals are level-triggered and internally synchronized.
NMI	46	I	The Non-Maskable Interrupt input causes a Type 2 interrupt. An NMI transition from LOW to HIGH is latched and synchronized internally, and initiates the interrupt at the next instruction boundary. NMI must be asserted for at least one CLKOUT period. The Non-Maskable Interrupt cannot be avoided by programming.
INT0 INT1/SELECT INT2/INTA0 INT3/INTA1/IRQ	45 44 42 41	 	Maskable Interrupt Requests can be requested by activating one of these pins. When configured as inputs, these pins are active HIGH. Interrupt Requests are synchronized internally. INT2 and INT3 may be configured to provide active-LOW interrupt-acknowledge output signals. All interrupt inputs may be configured to be either edge- or level-triggered. To ensure recognition, all interrupt requests must remain active until the interrupt is acknowledged. When Slave Mode is selected, the function of these pins changes (see Interrupt Controller section of this data sheet).
A19/S6 A18/S5 A17/S4 A16/S3	65 66 67 68	0 0 0	Address Bus Outputs (16–19) and Bus Cycle Status (3–6) indicate the four most significant address bits during T ₁ . These signals are active HIGH. During T ₂ , T ₃ , T _W and T ₄ , the S6 pin is LOW to indicate a CPU-initiated bus cycle or HIGH to indicate a DMA-initiated or refresh bus cycle. During the same T-states, S3, S4 and S5 are always LOW. These outputs are floated during bus hold or reset.
AD15 AD14 AD13 AD12 AD11 AD10 AD9 AD8 AD7 AD6 AD5 AD4 AD3 AD2 AD1 AD0	1 3 5 7 10 12 14 16 2 4 6 8 11 13 15	1/0 1/0 1/0 1/0 1/0 1/0 1/0 1/0 1/0 1/0	Address/Data Bus $(0-15)$ signals constitute the time multiplexed memory or I/O address (T_1) and data (T_2, T_3, T_W) and (T_4) bus. The bus is active HIGH. (T_4) is analogous to BHE for the lower byte of the data bus, pins (T_4) through (T_4) when a byte is to be transferred onto the lower portion of the bus in memory or I/O operations. These pins are floated during a bus hold or reset.



Table 1. M80C186XL Pin Description (Continued)

Symbol	PGA Pin No.	Туре			Name and Function				
BHE	64	0	The BHE (Bus High Enable) signal is analogous to A0 in that it is used to enable data on to the most significant half of the data bus, pins D15–D8. BHE will be LOW during T ₁ when the upper byte is transferred and will remain LOW through T ₃ AND T _W . BHE does not need to be latched. BHE will float during HOLD or RESET. In Enhanced Mode, BHE will also be used to signify DRAM refresh cycles. A refresh cycle is indicated by both BHE and A0 being HIGH.						
					BHE and A0 Encodings				
			BHE Value	A0 Value	Function				
			0 0 1 1	0 1 0 1	Word Transfer Byte Transfer on upper half of data bus (D15–D8) Byte Transfer on lower half of data bus (D ₇ –D ₀) Refresh				
ALE/QS0	61	0	to latch	Address Latch Enable/Queue Status 0 is provided by the M80C186XL to latch the address. ALE is active HIGH, with addresses guaranteed valid on the trailing edge.					
WR/QS1	63	0	Write Strobe/Queue Status 1 indicates that the data on the bus is to be written into a memory or an I/O device. It is active LOW, and floats during bus hold or reset. When the M80C186XL is in Queue Status Mode, the ALE/QS0 and WR/QS1 pins provide information about processor/instruction queue interaction.						
			QS1	QS0	Queue Operation				
			0 0 1 1	0 1 1 0	No queue operation First opcode byte fetched from the queue Subsequent byte fetched from the queue Empty the queue				
RD/QSMD	62	O/I	M80C18 not to g ensures pin is sa RD, and	B6XL is pe to LOW be that RD/ ampled to I WR, or q	n active LOW signal which indicates that the erforming a memory or I/O read cycle. It is guaranteed afore the A/D bus is floated. An internal pull-up QSMD is HIGH during RESET. Following RESET the determine whether the M80C186XL is to provide ALE, ueue status information. To enable Queue Status e connected to GND. RD will float during bus HOLD.				
ARDY	55	I	Asynchronous Ready informs the M80C186XL that the addressed memory space or I/O device will complete a data transfer. The ARDY pin accepts a rising edge that is asynchronous to CLKOUT and is active HIGH. The falling edge of ARDY must be synchronized to the M80C186XL clock. Connecting ARDY HIGH will always assert the ready condition to the CPU. If this line is unused, it should be tied LOW						
SRDY	49	I	memory pin acce SRDY a by elimi synchor assert ti	ready condition to the CPU. If this line is unused, it should be tied LOW to yield control to the SRDY pin. Synchronous Ready informs the M80C186XL that the addressed memory space or I/O device will complete a data transfer. The SRDY pin accepts an active-HIGH input synchronized to CLKOUT. The use of SRDY allows a relaxed system timing over ARDY. This is accomplished by elimination of the one-half clock cycle required to internally synchonize the ARDY input signal. Connecting SRDY high will always assert the ready condition to the CPU. If this line is unused, it should be tied LOW to yield control to the ARDY pin.					



Table 1. M80C186XL Pin Description (Continued)

Symbol	PGA Pin No.	Туре				Name and Function				
LOCK	48	0	cont requ of th the L No ir	LOCK output indicates that other system bus masters are not to gain control of the system bus. LOCK is active LOW. The LOCK signal is requested by the LOCK prefix instruction and is activated at the beginning of the first data cycle associated with the instruction immediately following the LOCK prefix. It remains active until the completion of that instruction. No instruction prefetching will occur while LOCK is asserted. LOCK floats during bus hold or reset.						
\$0 \$1	52 53	0		cycle s matior		$\overline{S0} - \overline{S2}$ are encoded to provide bus-transaction				
<u>S2</u>	54	0			M	80C186XL Bus Cycle Status Information				
			<u>S2</u>	<u>S1</u>	<u>50</u>	Bus Cycle Initiated				
			0 0 0 0 1 1 1	0						
					•	oat during HOLD. as a logical M/I \overline{O} indicator, and $\overline{S1}$ as a DT/ \overline{R} indicator.				
HOLD HLDA	50 51	0	HOL resp the M dete M80 and In Er	HOLD indicates that another bus master is requesting the local bus. The HOLD input is active HIGH. The M80C186XL generates HLDA (HIGH) in response to a HOLD request. Simultaneous with the issuance of HLDA, the M80C186XL will float the local bus and control lines. After HOLD is detected as being LOW, the M80C186XL will lower HLDA. When the M80C186XL needs to run another bus cycle, it will again drive the local bus and control lines. In Enhanced Mode, HLDA will go low when a DRAM refresh cycle is pending in the M80C186XL and an external bus master has control of the						
						o the external master to relinquish the bus by lowering M80C186XL may execute the refresh cycle.				
ŪCS	34	O/I	refer mem UCS UCS held assu UCS	Upper Memory Chip Select is an active LOW output whenever a memory reference is made to the defined upper portion (1K–256K block) of memory. UCS does not float during bus hold. The address range activating UCS is software programmable. UCS and LCS are sampled upon the rising edge of RES. If both pins are held low, the M80C186XL will enter ONCE Mode. In ONCE Mode all pins assume a high impedance state and remain so until a subsequent RESET. UCS has a weak internal pullup that is active during RESET to ensure that the M80C186XL does not enter ONCE Mode inadvertently.						
<u>LCS</u>	33	O/I	mad float	e to th	e defin J bus H	hip Select is active LOW whenever a memory reference is led lower portion (1K-256K) of memory. LCS does not lOLD. The address range activating LCS is software				



Table 1. M80C186XL Pin Description (Continued)

	Table 1. Mouc Tooks Pin Description (Continued)					
Symbol	PGA Pin No.	Туре	Name and Function			
ICS (Continued)			UCS and LCS are sampled upon the rising edge of RES. If both pins are held low, the M80C186XL will enter ONCE Mode. In ONCE Mode all pins assume a high impedance state and remain so until a subsequent RESET. LCS has a weak internal pullup that is active only during RESET to ensure that the M80C186XL does not enter ONCE mode inadvertently.			
MCS0/PEREQ MCS1/ERROR MCS2 MCS3/NPS	38 37 36 35	0/I 0/I 0	Mid-Range Memory Chip Select signals are active LOW when a memory reference is made to the defined mid-range portion of memory (8K–512K). These lines do not float during bus HOLD. The address ranges activating MCS0–3 are software programmable.			
			In Enhanced Mode, MCSO becomes a PEREQ input (Processor Extension Request). When connected to the Math Coprocessor, this input is used to signal the M80C186XL when to make numeric data transfers to and from the coprocessor. MCSO becomes NPS (Numeric Processor Select) which may only be activated by communication to the 80C187. MCSO becomes ERROR in Enhanced Mode and is used to signal numerics coprocessor errors. MCSO/PEREQ and MCSO/ERROR have weak internal pullups			
			which are active during reset.			
PCS0 PCS1 PCS2 PCS3 PCS4	25 27 28 29 30	0 0 0 0	Peripheral Chip Select signals 0–4 are active LOW when a reference is made to the defined peripheral area (64K byte I/O or 1 MByte memory space). These lines do not float during bus HOLD. The address ranges activating PCS0–4 are software programmable.			
PCS5/A1	31	0	Peripheral Chip Select 5 or Latched A1 may be programmed to provide a sixth peripheral chip select, or to provide an internally latched A1 signal. The address range activating PCS5 is software-programmable. PCS5/A1 does not float during bus HOLD. When programmed to provide latched A1, this pin will retain the previously latched value during HOLD.			
PCS6/A2	32	0	Peripheral Chip Select 6 or Latched A2 may be programmed to provide a seventh peripheral chip select, or to provide an internally latched A2 signal. The address range activating PCS6 is software-programmable. PCS6/A2 does not float during bus HOLD. When programmed to provide latched A2, this pin will retain the previously latched value during HOLD.			
DT/R	40	0	Data Transmit/Receive controls the direction of data flow through an external data bus transceiver. When LOW, data is transferred to the M80C186XL. When HIGH the M80C186XL places write data on the data bus. DT/R floats during a bus hold or reset.			
DEN	39	0	Data Enable is provided as a data bus transceiver output enable. DEN is active LOW during each memory and I/O access (including 80C187 access). DEN is HIGH whenever DT/R changes state. During RESET, DEN is driven HIGH for one clock, then floated. DEN also floats during HOLD.			
N.C.	_	_	Not connected. To maintain compatibility with future products, do not connect to these pins.			



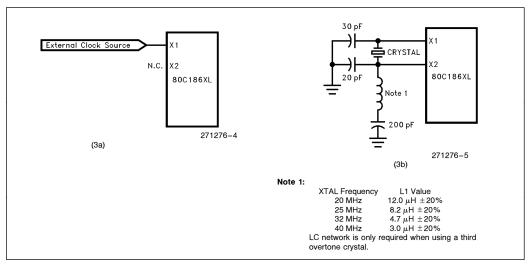


Figure 3. M80C186XL Oscillator Configurations (see text)

INTRODUCTION

The following Functional Description describes the base architecture of the M80C186XL. The M80C186XL is a very high integration 16-bit microprocessor. It combines 15–20 of the most common microprocessor system components onto one chip. The M80C186XL is object code compatible with the 8086/8088 microprocessors and adds 10 new instruction types to the 8086/8088 instruction set.

The M80C186XL has two major modes of operation, Compatible and Enhanced. In Compatible Mode the M80C186XL is completely compatible with NMOS 80186, with the exception of 8087 support. The Enhanced mode adds three new features to the system design. These are Power-Save control, Dynamic RAM refresh, and an asynchronous Numerics Coprocessor interface.

M80C186XL BASE ARCHITECTURE

M80C186XL Clock Generator

The M80C186XL provides an on-chip clock generator for both internal and external clock generation. The clock generator features a crystal oscillator, a divide-by-two counter, synchronous and asynchronous ready inputs, and reset circuitry.

The M80C186XL oscillator circuit is designed to be used either with a parallel resonant fundamental or

third-overtone mode crystal, depending upon the frequency range of the application. This is used as the time base for the M80C186XL.

The output of the oscillator is not directly available outside the M80C186XL. The recommended crystal configuration is shown in Figure 3b. When used in third-overtone mode, the tank circuit is recommended for stable operation. Alternately, the oscillator may be driven from an external source as shown in Figure 3a.

The crystal or clock frequency chosen must be twice the required processor operating frequency due to the internal divide by two counter. This counter is used to drive all internal phase clocks and the external CLKOUT signal. CLKOUT is a 50% duty cycle processor clock and can be used to drive other system components. All AC Timings are referenced to CLKOUT.

Intel recommends the following values for crystal selection parameters.

Temperature Range: Application Specific ESR (Equivalent Series Resistance): 60Ω max C_0 (Shunt Capacitance of Crystal): 7.0 pF max C_1 (Load Capacitance): 20 pF ± 5 pF Drive Level: 2 mW max



Bus Interface Unit

The M80C186XL provides a local bus controller to generate the local bus control signals. In addition, it employs a HOLD/HLDA protocol for relinquishing the local bus to other bus masters. It also provides outputs that can be used to enable external buffers and to direct the flow of data on and off the local bus.

The bus controller is responsible for generating 20 bits of address, read and write strobes, bus cycle status information and data (for write operations) information. It is also responsible for reading data from the local bus during a read operation. Synchronous and asynchronous ready input pins are provided to extend a bus cycle beyond the minimum four states (clocks).

The M80C186XL bus controller also generates two control signals (\overline{DEN} and DT/\overline{R}) when interfacing to external transceiver chips. This capability allows the addition of transceivers for simple buffering of the multiplexed address/data bus.

During RESET the local bus controller will perform the following action:

- Drive DEN, RD and WR HIGH for one clock cycle, then float them.
- Drive S0-S2 to the inactive state (all HIGH) and then float.
- Drive LOCK HIGH and then float.
- Float AD0-15, A16-19, BHE, DT/R.
- Drive ALE LOW
- Drive HLDA LOW.

RD/QSMD, UCS, LCS, MCS0/PEREQ, MCS1/ERROR and TEST/BUSY pins have internal pullup devices which are active while RES is applied. Excessive loading or grounding certain of these pins causes the M80C186XL to enter an alternative mode of operation:

- RD/QSMD low results in Queue Status Mode.
- UCS and LCS low results in ONCE Mode.
- TEST/BUSY low (and high later) results in Enhanced Mode.

M80C186XL PERIPHERAL ARCHITECTURE

All the M80C186XL integrated peripherals are controlled by 16-bit registers contained within an internal 256-byte control block. The control block may be mapped into either memory or I/O space. Internal logic will recognize control block addresses and respond to bus cycles. An offset map of the 256-byte control register block is shown in Figure 4.

Chip-Select/Ready Generation Logic

The M80C186XL contains logic which provides programmable chip-select generation for both memories and peripherals. In addition, it can be programmed to provide READY (or WAIT state) generation. It can also provide latched address bits A1 and A2. The chip-select lines are active for all memory and I/O cycles in their programmed areas, whether they be generated by the CPU or by the integrated DMA unit

The M80C186XL provides 6 memory chip select outputs for 3 address areas; upper memory, lower memory, and midrange memory. One each is provided for upper memory and lower memory, while four are provided for midrange memory.

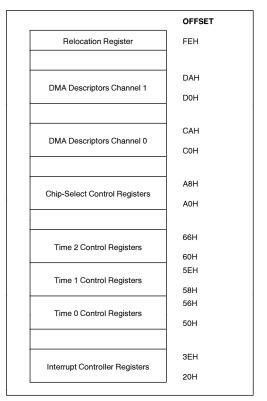


Figure 4. Internal Register Map

The M80C186XL provides a chip select, called $\overline{\text{UCS}}$, for the top of memory. The top of memory is usually used as the system memory because after reset the M80C186XL begins executing at memory location FFFF0H.



The M80C186XL provides a chip select for low memory called $\overline{\text{LCS}}$. The bottom of memory contains the interrupt vector table, starting at location 00000H.

The M80C186XL provides four $\overline{\text{MCS}}$ lines which are active within a user-locatable memory block. This block can be located within the M80C186XL 1 Mbyte memory address space exclusive of the areas defined by $\overline{\text{UCS}}$ and $\overline{\text{LCS}}$. Both the base address and size of this memory block are programmable.

The M80C186XL can generate chip selects for up to seven peripheral devices. These chip selects are active for seven contiguous blocks of 128 bytes above a programmable base address. The base address may be located in either memory or I/O space.

The M80C186XL can generate a READY signal internally for each of the memory or peripheral $\overline{\text{CS}}$ lines. The number of WAIT states to be inserted for each peripheral or memory is programmable to provide 0–3 wait states for all accesses to the area for which the chip select is active. In addition, the M80C186XL may be programmed to either ignore external READY for each chip-select range individually or to factor external READY with the integrated ready generator.

Upon RESET, the Chip-Select/Ready Logic will perform the following actions:

- All chip-select outputs will be driven HIGH.
- Upon leaving RESET, the UCS line will be programmed to provide chip selects to a 1K block with the accompanying READY control bits set at 011 to insert 3 wait states in conjunction with external READY (i.e., UMCS resets to FFFBH).
- No other chip select or READY control registers have any predefined values after RESET. They will not become active until the CPU accesses their control registers.

DMA Unit

The M80C186XL DMA controller provides two independent high-speed DMA channels. Data transfers can occur between memory and I/O spaces (e.g., Memory to I/O) or within the same space (e.g., Memory to Memory or I/O to I/O). Data can be transferred either in bytes (8 bits) or in words (16 bits) to or from even or odd addresses. Each DMA channel maintains both a 20-bit source and destination pointer which can be optionally incremented or decremented after each data transfer (by one or two depending on byte or word transfers). Each data transfer consumes 2 bus cycles (a minimum of 8 clocks), one cycle to fetch data and the other to store data.

Timer/Counter Unit

The M80C186XL provides three internal 16-bit programmable timers. Two of these are highly flexible and are connected to four external pins (2 per timer). They can be used to count external events, time external events, generate nonrepetitive waveforms, etc. The third timer is not connected to any external pins, and is useful for real-time coding and time delay applications. In addition, the third timer can be used as a prescaler to the other two, or as a DMA request source.

Interrupt Control Unit

The M80C186XL can receive interrupts from a number of sources, both internal and external. The M80C186XL has 5 external and 2 internal interrupt sources (Timer/Couners and DMA). The internal interrupt controller serves to merge these requests on a priority basis, for individual service by the CPU.

Enhanced Mode Operation

In Compatible Mode the M80C186XL operates with all the features of the NMOS 80186, with the exception of 8087 support (i.e. no math coprocessing is possible in Compatible Mode). Queue-Status information is still available for design purposes other than 8087 support.

All the Enhanced Mode features are completely masked when in Compatible Mode. A write to any of the Enhanced Mode registers will have no effect, while a read will not return any valid data.

In Enhanced Mode, the M80C186XL will operate with Power-Save, DRAM refresh, and numerics coprocessor support in addition to all the Compatible Mode features.

If connected to a math coprocessor, this mode will be invoked automatically. Without an NPX, this mode can be entered by tying the RESET output signal from the M80C186XL to the TEST/BUSY input.

Queue-Status Mode

The queue-status mode is entered by strapping the $\overline{\text{RD}}$ pin low. $\overline{\text{RD}}$ is sampled at RESET and if LOW, the M80C186XL will reconfigure the ALE and $\overline{\text{WR}}$ pins to be QS0 and QS1 respectively. This mode is available on the M80C186XL in both Compatible and Enhanced Modes.



DRAM Refresh Control Unit

The Refresh Control Unit (RCU) automatically generates DRAM refresh bus cycles. The RCU operates only in Enhanced Mode. After a programmable period of time, the RCU generates a memory read request to the BIU. If the address generated during a refresh bus cycle is within the range of a properly programmed chip select, that chip select will be activated when the BIU executes the refresh bus cycle.

Power-Save Control

The M80C186XL, when in Enhanced Mode, can enter a power saving state by internally dividing the processor clock frequency by a programmable factor. This divided frequency is also available at the CLKOUT pin.

All internal logic, including the Refresh Control Unit and the timers, have their clocks slowed down by the division factor. To maintain a real time count or a fixed DRAM refresh rate, these peripherals must be re-programmed when entering and leaving the power-save mode.

Interface for 80C187 Math Coprocessor

In Enhanced Mode, three of the mid-range memory chip selects are redefined according to Table 2 for use with the 80C187. The fourth chip select, MCS2 functions as in compatible mode, and may be pro-

grammed for activity with ready logic and wait states accordingly. As in Compatible Mode, MCS2 will function for one-fourth a programmed block size.

Table 2. MCS Assignments

Compatible Mode	Enhanced Mode					
MCS0	PEREQ	Processor Extension Request				
MCS1	ERROR	NPX Error				
MCS2	MCS2	Mid-Range Chip Select				
MCS3	NPS	Numeric Processor Select				

ONCE Test Mode

To facilitate testing and inspection of devices when fixed into a target system, the M80C186XL has a test mode available which allows all pins to be placed in a high-impedance state. ONCE stands for "ON Circuit Emulation". When placed in this mode, the M80C186XL will put all pins in the high-impedance state until RESET.

The ONCE mode is selected by tying the $\overline{\text{UCS}}$ and the $\overline{\text{LCS}}$ LOW during RESET. These pins are sampled on the low-to-high transition of the $\overline{\text{RES}}$ pin. The $\overline{\text{UCS}}$ and the $\overline{\text{LCS}}$ pins have weak internal pullup resistors similar to the $\overline{\text{RD}}$ and $\overline{\text{TEST}}/\text{BUSY}$ pins to guarantee ONCE Mode is not entered inadvertently during normal operation. $\overline{\text{LCS}}$ and $\overline{\text{UCS}}$ must be held low at least one clock after $\overline{\text{RES}}$ goes high to guarantee entrance into ONCE Mode.



ABSOLUTE MAXIMUM RATINGS*

Case Temperature under Bias -55° C to $+125^{\circ}$ C
Storage Temperature $\dots -65^{\circ}\text{C}$ to $+150^{\circ}\text{C}$
Voltage on Any Pin with Respect to Ground 1.0V to +7.0V
/Package Power Dissipation

NOTICE: This data sheet contains information on products in the sampling and initial production phases of development. It is valid for the devices indicated in the revision history. The specifications are subject to change without notice.

*WARNING: Stressing the device beyond the "Absolute Maximum Ratings" may cause permanent damage. These are stress ratings only. Operation beyond the "Operating Conditions" is not recommended and extended exposure beyond the "Operating Conditions" may affect device reliability.

NOTICE: The specifications are subject to change without notice.

DC CHARACTERISTICS $T_C = -55^{\circ}C$ to $+125^{\circ}C$, $V_{CC} = 5V \pm 10\%$

Symbol	Parameter	Min	Max	Units	Test Conditions
V _{IL}	Input Low Voltage (Except X1)	-0.5	0.2 V _{CC} - 0.3	V	
V _{IL1}	Clock Input Low Voltage (X1)	-0.5	0.6	V	
V _{IH}	Input High Voltage (All except X1 and RES)	$0.2 V_{CC} + 0.9$	V _{CC} + 0.5	V	
V _{IH1}	Input High Voltage (RES)	3.0	V _{CC} + 0.5	V	
V_{IH2}	Clock Input High Voltage (X1)	3.9	V _{CC} + 0.5	V	
V _{OL}	Output Low Voltage		0.45	٧	$I_{OL} = 2.5 \text{ mA (S0, 1, 2)}$ $I_{OL} = 2.0 \text{ mA (others)}$
V_{OH}	Output High Voltage	2.4	V _{CC}	V	$I_{OH} = -2.4 \text{ mA } @ 2.4 \text{V} (4)$
		V _{CC} - 0.5	V _{CC}	V	$I_{OH} = -200 \mu\text{A} @ V_{CC} - 0.5(4)$
Icc	Power Supply Current		100	mA	@ 20 MHz, -55° C V _{CC} = 5.5V(3)
			90	mA	@16 MHz, -55° C V _{CC} = 5.5V(3)
			80	mA	@ 12.5 MHz, -55°C V _{CC} = 5.5V (3)
			70	mA	@ 10 MHz, -55°C V _{CC} = 5.5V ⁽³⁾
ILI	Input Leakage Current		± 10	μΑ	$ \label{eq:controller} \begin{array}{l} @\ 0.5\ MHz, \\ 0.45V \leq V_{IN} \leq V_{CC} \end{array} $
I _{LO}	Output Leakage Current		± 10	μΑ	@ 0.5 MHz, $0.45V \le V_{OUT} \le V_{CC}^{(1)}$
V _{CLO}	Clock Output Low		0.45	V	$I_{CLO} = 4.0 \text{ mA}$



DC CHARACTERISTICS (Continued) $T_C = -55^{\circ}C$ to $+125^{\circ}C$, $V_{CC} = 5V \pm 10\%$

Symbol	Parameter	Min	Max	Units	Test Conditions
V _{CHO}	Clock Output High	V _{CC} - 0.5		V	$I_{CHO} = -500 \mu A$
C _{IN}	Input Capacitance		10	pF	@ 1 MHz(2)
C _{IO}	Output or I/O Capacitance		20	pF	@ 1 MHz(2)

NOTES:

- 1. Pins being floated during HOLD or by invoking the ONCE Mode.
 2. Characterization conditions are a) Frequency = 1 MHz; b) Unmeasured pins at GND; c) V_{IN} at + 5.0V or 0.45V. This parameter is not tested.
- 3. Current is measured with the device in RESET with X1 and X2 driven and all other non-power pins open.

 4. RD/QSMD, UCS, LCS, MCS0/PEREQ, MCS1/ERROR and TEST/BUSY pins have internal pullup devices. Loading some of these pins above I_{OH} = $-200~\mu$ A can cause the M80C186XL to go into alternative modes of operation. See the section on Local Bus Controller and Reset for details.



MAJOR CYCLE TIMINGS (READ CYCLE)

T_C = -55° C to $+125^{\circ}$ C, V_{CC} = $5V \pm 10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with C_L = 50 pF. For AC tests, input V_{IL} = 0.45V and V_{IH} = 2.4V except at X1 where V_{IH} = V_{CC} - 0.5V.

		Values					
Symbol	Parameter	M80C186)	(L	M80C186XI	L12	Unit	Test Conditions
		Min	Max	Min	Max		Oomandone
M80C186	XL GENERAL TIMING REQU	IREMENTS (Lis	ted Mo	re Than Once)			
T _{DVCL}	Data in Setup (A/D)	15		15		ns	
T _{CLDX}	Data in Hold (A/D)	3		3		ns	
M80C186	XL GENERAL TIMING RESPO	ONSES (Listed I	More T	han Once)	•		
T _{CHSV}	Status Active Delay	3	45	3	35	ns	
T _{CLSH}	Status Inactive Delay	3	46	3	35	ns	
T _{CLAV}	Address Valid Delay	3	44	3	36	ns	
T _{CLAX}	Address Hold	0		0		ns	
T _{CLDV}	Data Valid Delay	3	40	3	36	ns	
T _{CHDX}	Status Hold Time	10		10		ns	
T _{CHLH}	ALE Active Delay		30		25	ns	
T _{LHLL}	ALE Width	T _{CLCL} - 15		T _{CLCL} - 15		ns	
T _{CHLL}	ALE Inactive Delay		30		25	ns	
T _{AVLL}	Address Valid to ALE Low	T _{CLCH} - 18		T _{CLCH} - 15		ns	Equal Loading
T _{LLAX}	Address Hold from ALE Inactive	T _{CHCL} - 15		T _{CHCL} - 15		ns	Equal Loading
T _{AVCH}	Address Valid to Clock High	0		0		ns	
T _{CLAZ}	Address Float Delay	T _{CLAX}	30	T _{CLAX}	25	ns	
T _{CLCSV}	Chip-Select Active Delay	3	42	3	33	ns	
T _{CXCSX}	Chip-Select Hold from Command Inactive	T _{CLCH} - 10		T _{CLCH} - 10		ns	Equal Loading
T _{CHCSX}	Chip-Select Inactive Delay	3	35	3	30	ns	
T _{DXDL}	DEN Inactive to DT/R Low	0		0		ns	Equal Loading
T _{CVCTV}	Control Active Delay 1	3	44	3	37	ns	
T _{CVDEX}	DEN Inactive Delay	3	44	3	37	ns	
T _{CHCTV}	Control Active Delay 2	3	44	3	37	ns	
T _{CLLV}	LOCK Valid/Invalid Delay	3	40	3	37	ns	
M80C186	XL TIMING RESPONSES (Re	ad Cycle)					
T _{AZRL}	Address Float to RD Active	0		0		ns	
T _{CLRL}	RD Active Delay	3	44	3	37	ns	
T _{RLRH}	RD Pulse Width	2T _{CLCL} - 30		2T _{CLCL} - 25		ns	
T _{CLRH}	RD Inactive Delay	3	44	3	37	ns	
T _{RHLH}	RD Inactive to ALE High	T _{CLCH} - 14		T _{CLCH} - 14		ns	Equal Loading
T _{RHAV}	RD Inactive to Address Active	T _{CLCL} - 15		T _{CLCL} - 15		ns	Equal Loading



MAJOR CYCLE TIMINGS (READ CYCLE)

 $T_C=-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$, $V_{CC}=5\text{V}\pm10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with $C_L=50$ pF. For AC tests, input $V_{IL}=0.45\text{V}$ and $V_{IH}=2.4\text{V}$ except at X1 where $V_{IH}=V_{CC}-0.5\text{V}$.

		Values					
Symbol	Parameter	M80C186X	L16	M80C186XI	_20	Unit	Test Conditions
		Min	Max	Min	Max		
M80C186	XL GENERAL TIMING REQU	IREMENTS (Lis	ted Mo	re Than Once)			
T _{DVCL}	Data in Setup (A/D)	15		10		ns	
T _{CLDX}	Data in Hold (A/D)	3		3		ns	
M80C186	SXL GENERAL TIMING RESPO	ONSES (Listed I	More T	han Once)	•	•	
T _{CHSV}	Status Active Delay	1	31	1	25	ns	
T _{CLSH}	Status Inactive Delay	1	30	1	25	ns	
T _{CLAV}	Address Valid Delay	1	33	1	27	ns	
T _{CLAX}	Address Hold	0		0		ns	
T _{CLDV}	Data Valid Delay	1	33	1	27	ns	
T _{CHDX}	Status Hold Time	10		10		ns	
T _{CHLH}	ALE Active Delay		20		20	ns	
T _{LHLL}	ALE Width	T _{CLCL} - 15		T _{CLCL} - 15		ns	
T _{CHLL}	ALE Inactive Delay		20		20	ns	
T _{AVLL}	Address Valid to ALE Low	T _{CLCH} - 15		T _{CLCH} - 10		ns	Equal Loading
T _{LLAX}	Address Hold from ALE Inactive	T _{CHCL} - 15		T _{CHCL} - 10		ns	Equal Loading
T _{AVCH}	Address Valid to Clock High	0		0		ns	
T _{CLAZ}	Address Float Delay	T _{CLAX}	20	T _{CLAX}	20	ns	
T _{CLCSV}	Chip-Select Active Delay	1	30	1	25	ns	
T _{CXCSX}	Chip-Select Hold from Command Inactive	t _{CLCH} - 10		T _{CLCH} - 10		ns	Equal Loading
T _{CHCSX}	Chip-Select Inactive Delay	1	25	1	20	ns	
T _{DXDL}	DEN Inactive to DT/R Low	0		0		ns	Equal Loading
T _{CVCTV}	Control Active Delay 1	1	31	1	22	ns	
T _{CVDEX}	DEN Inactive Delay	1	31	1	22	ns	
T _{CHCTV}	Control Active Delay 2	1	31	1	22	ns	
T _{CLLV}	LOCK Valid/Invalid Delay	1	35	1	22	ns	
M80C186	XL TIMING RESPONSES (Re	ad Cycle)			•		
T _{AZRL}	Address Float to RD Active	0		0		ns	
T _{CLRL}	RD Active Delay	1	31	1	27	ns	
T _{RLRH}	RD Pulse Width	2T _{CLCL} - 25		2T _{CLCL} - 20		ns	
T _{CLRH}	RD Inactive Delay	1	31	1	27	ns	
T _{RHLH}	RD Inactive to ALE High	T _{CLCH} - 14		T _{CLCH} - 14		ns	Equal Loading
T _{RHAV}	RD Inactive to Address Active	T _{CLCL} – 15		T _{CLCL} – 15		ns	Equal Loading



MAJOR CYCLE TIMINGS (WRITE CYCLE)

T_C = -55° C to $+125^{\circ}$ C, V_{CC} = 5V $\pm 10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with C_L = 50 pF. For AC tests, input V_{IL} = 0.45V and V_{IH} = 2.4V except at X1 where V_{IH} = V_{CC} - 0.5V.

			Val	ues			
Symbol	Parameter	M80C186)	(L	M80C186XI	L12	Unit	Test Conditions
		Min	Max	Min	Max		Conditions
M80C186	XL GENERAL TIMING RESPO	NSES (Listed N	lore Th	nan Once)	•	•	
T _{CHSV}	Status Active Delay	3	45	3	35	ns	
T _{CLSH}	Status Inactive Delay	3	46	3	35	ns	
T _{CLAV}	Address Valid Delay	3	44	3	36	ns	
T _{CLAX}	Address Hold	0		0		ns	
T _{CLDV}	Data Valid Delay	3	40	3	36	ns	
T _{CHDX}	Status Hold Time	10		10		ns	
T _{CHLH}	ALE Active Delay		30		25	ns	
T _{LHLL}	ALE Width	T _{CLCL} - 15		T _{CLCL} - 15		ns	
T _{CHLL}	ALE Inactive Delay		30		25	ns	
T _{AVLL}	Address Valid to ALE Low	T _{CLCH} - 18		T _{CLCH} - 15		ns	Equal Loading
T _{LLAX}	Address Hold from ALE Inactive	T _{CHCL} - 15		T _{CHCL} - 15		ns	Equal Loading
T _{AVCH}	Address Valid to Clock High	0		0		ns	
T _{CLDOX}	Data Hold Time	3		3		ns	
T _{CVCTV}	Control Active Delay 1	3	44	3	37	ns	
T _{CVCTX}	Control Inactive Delay	3	44	3	37	ns	
T _{CLCSV}	Chip-Select Active Delay	3	42	3	33	ns	
T _{CXCSX}	Chip-Select Hold from Command Inactive	T _{CLCH} - 10		T _{CLCH} - 10		ns	Equal Loading
T _{CHCSX}	Chip-Select Inactive Delay	3	35	3	30	ns	
T _{DXDL}	DEN Inactive to DT/R Low	0		0		ns	Equal Loading
T _{CLLV}	LOCK Valid/Invalid Delay	3	40	3	37	ns	
M80C186	XL TIMING RESPONSES (Wri	te Cycle)					
T _{WLWH}	WR Pulse Width	2T _{CLCL} - 30		2T _{CLCL} - 25		ns	
T _{WHLH}	WR Inactive to ALE High	T _{CLCH} - 14		T _{CLCH} - 14		ns	Equal Loading
T _{WHDX}	Data Hold after WR	T _{CLCL} – 34		T _{CLCL} – 20		ns	Equal Loading
T _{WHDEX}	WR Inactive to DEN Inactive	T _{CLCH} - 10		T _{CLCH} - 10		ns	Equal Loading



MAJOR CYCLE TIMINGS (WRITE CYCLE)

 $T_C=-55^{\circ}C$ to $+125^{\circ}C,~V_{CC}=5V~\pm10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with $C_L=50$ pF. For AC tests, input $V_{IL}=0.45V$ and $V_{IH}=2.4V$ except at X1 where $V_{IH}=V_{CC}-0.5V$.

			Val	ues			
Symbol	Parameter	M80C186XI	L16	M80C186XI	L20	Unit	Test Conditions
		Min	Max	Min	Max		Conditions
M80C186	XL GENERAL TIMING RESPO	NSES (Listed N	lore Th	nan Once)	•	•	
T _{CHSV}	Status Active Delay	1	31	1	25	ns	
T _{CLSH}	Status Inactive Delay	1	30	1	25	ns	
T _{CLAV}	Address Valid Delay	1	33	1	27	ns	
T _{CLAX}	Address Hold	0		0		ns	
T _{CLDV}	Data Valid Delay	1	33	1	27	ns	
T _{CHDX}	Status Hold Time	10		10		ns	
T _{CHLH}	ALE Active Delay		20		20	ns	
T _{LHLL}	ALE Width	T _{CLCL} - 15		T _{CLCL} - 15		ns	
T _{CHLL}	ALE Inactive Delay		20		20	ns	
T _{AVLL}	Address Valid to ALE Low	T _{CLCH} – 15		T _{CLCH} - 10		ns	Equal Loading
T _{LLAX}	Address Hold from ALE Inactive	T _{CHCL} - 15		T _{CHCL} - 10		ns	Equal Loading
T _{AVCH}	Address Valid to Clock High	0		0		ns	
T _{CLDOX}	Data Hold Time	1		1		ns	
T _{CVCTV}	Control Active Delay 1	1	31	1	25	ns	
T _{CVCTX}	Control Inactive Delay	1	31	1	25	ns	
T _{CLCSV}	Chip-Select Active Delay	1	30	1	25	ns	
T _{CXCSX}	Chip-Select Hold from Command Inactive	T _{CLCH} - 10		T _{CLCH} - 10		ns	Equal Loading
T _{CHCSX}	Chip-Select Inactive Delay	1	25	1	20	ns	
T _{DXDL}	DEN Inactive to DT/R Low	0		0		ns	Equal Loading
T _{CLLV}	LOCK Valid/Invalid Delay	1	35	1	22	ns	
M80C186	XL TIMING RESPONSES (Wri	te Cycle)	•		•	•	
T _{WLWH}	WR Pulse Width	2T _{CLCL} - 25		2T _{CLCL} - 20		ns	
T _{WHLH}	WR Inactive to ALE High	T _{CLCH} - 14		T _{CLCH} - 14		ns	Equal Loading
T _{WHDX}	Data Hold after WR	T _{CLCL} – 20		T _{CLCL} – 15		ns	Equal Loading
T _{WHDEX}	WR Inactive to DEN Inactive	T _{CLCH} - 10		T _{CLCH} - 10		ns	Equal Loading



MAJOR CYCLE TIMINGS (INTERRUPT ACKNOWLEDGE CYCLE)

 $T_C=-55^{\circ}C$ to $+125^{\circ}C,\,V_{CC}=5V\pm10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with $C_L=50$ pF. For AC tests, input $V_{IL}=0.45V$ and $V_{IH}=2.4V$ except at X1 where $V_{IH}=V_{CC}-0.5V.$

			Val	ues			
Symbol	Parameter	M80C186	XL	M80C186X	L12	Unit	Test Conditions
		Min	Max	Min	Max		Oonanions
M80C186	XL GENERAL TIMING REQUI	REMENTS (Lis	ted Mo	re Than Once)		•	
T _{DVCL}	Data in Setup (A/D)	15		15		ns	
T_{CLDX}	Data in Hold (A/D)	3		3		ns	
M80C186	XL GENERAL TIMING RESPO	NSES (Listed	More T	han Once)			
T _{CHSV}	Status Active Delay	3	45	3	35	ns	
T _{CLSH}	Status Inactive Delay	3	46	3	35	ns	
T _{CLAV}	Address Valid Delay	3	44	3	36	ns	
T _{AVCH}	Address Valid to Clock High	0		0		ns	
T _{CLAX}	Address Hold	0		0		ns	
T _{CLDV}	Data Valid Delay	3	40	3	36	ns	
T _{CHDX}	Status Hold Time	10		10		ns	
T _{CHLH}	ALE Active Delay		30		25	ns	
T _{LHLL}	ALE Width	T _{CLCL} - 15		T _{CLCL} - 15		ns	
T _{CHLL}	ALE Inactive Delay		30		25	ns	
T _{AVLL}	Address Valid to ALE Low	T _{CLCH} - 18		T _{CLCH} - 15		ns	Equal Loading
T _{LLAX}	Address Hold to ALE Inactive	T _{CHCL} - 15		T _{CHCL} - 15		ns	Equal Loading
T _{CLAZ}	Address Float Delay	T _{CLAX}	30	T _{CLAX}	25	ns	
T _{CVCTV}	Control Active Delay 1	3	44	3	37	ns	
T _{CVCTX}	Control Inactive Delay	3	44	3	37	ns	
T _{DXDL}	DEN Inactive to DT/R Low	0		0		ns	Equal Loading
T _{CHCTV}	Control Active Delay 2	3	44	3	37	ns	
T _{CVDEX}	DEN Inactive Delay (Non-Write Cycles)	3	44	3	37	ns	
T _{CLLV}	LOCK Valid/Invalid Delay	3	40	3	37	ns	



MAJOR CYCLE TIMINGS (INTERRUPT ACKNOWLEDGE CYCLE)

 $T_C=-55^{\circ}C$ to $+125^{\circ}C,\,V_{CC}=5V\pm10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with $C_L=50$ pF. For AC tests, input $V_{IL}=0.45V$ and $V_{IH}=2.4V$ except at X1 where $V_{IH}=V_{CC}-0.5V.$

		2.17 0.000		ues	<u>,,, </u>		
Symbol	Parameter	M80C186X	L16	M80C186X	L20	Unit	Test Conditions
		Min	Max	Min	Max		Conditions
M80C186	XL GENERAL TIMING REQUI	REMENTS (Lis	ted Mo	re Than Once)		•	
T _{DVCL}	Data in Setup (A/D)	15		10		ns	
T _{CLDX}	Data in Hold (A/D)	1		1		ns	
M80C186	XL GENERAL TIMING RESPO	NSES (Listed	More T	han Once)			
T _{CHSV}	Status Active Delay	1	31	1	25	ns	
T _{CLSH}	Status Inactive Delay	1	30	1	25	ns	
T _{CLAV}	Address Valid Delay	1	33	1	27	ns	
T _{AVCH}	Address Valid to Clock High	0		0		ns	
T _{CLAX}	Address Hold	0		0		ns	
T _{CLDV}	Data Valid Delay	1	33	1	27	ns	
T _{CHDX}	Status Hold Time	10		10		ns	
T _{CHLH}	ALE Active Delay		20		20	ns	
T _{LHLL}	ALE Width	T _{CLCL} - 15		T _{CLCL} - 15		ns	
T _{CHLL}	ALE Inactive Delay		20		20	ns	
T _{AVLL}	Address Valid to ALE Low	T _{CLCH} - 15		T _{CLCH} - 10		ns	Equal Loading
T _{LLAX}	Address Hold to ALE Inactive	T _{CHCL} - 15		T _{CHCL} - 10		ns	Equal Loading
T _{CLAZ}	Address Float Delay	T _{CLAX}	20	T _{CLAX}	20	ns	
T _{CVCTV}	Control Active Delay 1	1	31	1	25	ns	
T _{CVCTX}	Control Inactive Delay	1	31	1	25	ns	
T _{DXDL}	DEN Inactive to DT/R Low	0		0		ns	Equal Loading
T _{CHCTV}	Control Active Delay 2	1	31	1	22	ns	
T _{CVDEX}	DEN Inactive Delay (Non-Write Cycles)	1	31	1	22	ns	
T _{CLLV}	LOCK Valid/Invalid Delay	1	35	1	22	ns	



SOFTWARE HALT CYCLE TIMINGS

 $T_C=-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$, $V_{CC}=5\text{V}\pm10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with $C_L=50$ pF. For AC tests, input $V_{IL}=0.45\text{V}$ and $V_{IH}=2.4\text{V}$ except at X1 where $V_{IH}=V_{CC}-0.5\text{V}$.

			Val	ues			-
Symbol	Parameter	M80C186XL		M80C186XL12		Unit	Test Conditions
		Min	Max	Min	Max		Contantions
M80C186	XL GENERAL TIMING REQU	IREMENTS (Li	sted Mo	ore Than Once)		
T _{CHSV}	Status Active Delay	3	45	3	35	ns	
T _{CLSH}	Status Inactive Delay	3	46	3	35	ns	
T _{CLAV}	Address Valid Delay	3	44	3	36	ns	
T _{CHLH}	ALE Active Delay		30		25	ns	
T _{LHLL}	ALE Width	T _{CLCL} - 15		T _{CLCL} - 15		ns	
T _{CHLL}	ALE Inactive Delay		30		25	ns	
T _{DXDL}	DEN Inactive to DT/R Low		0		0	ns	Equal Loading
T _{CHCTV}	Control Active Delay 2	3	44	3	37	ns	

			Val	ues			
Symbol	ParameterTarget	M80C186X	L16	M80C186XL20		Unit	Test Conditions
		Min	Max	Min	Max		Conditions
M80C186	XL GENERAL TIMING RESP	ONSES (Listed	More 1	Than Once)	•	•	
T _{CHSV}	Status Active Delay	3	31	3	25	ns	
T _{CLSH}	Status Inactive Delay	3	30	3	25	ns	
T _{CLAV}	Address Valid Delay	3	33	3	27	ns	
T _{CHLH}	ALE Active Delay		20		20	ns	
T _{LHLL}	ALE Width	T _{CLCL} - 15		T _{CLCL} - 15		ns	
T _{CHLL}	ALE Inactive Delay		20		20	ns	
T _{DXDL}	DEN Inactive to DT/R Low		0		0	ns	Equal Loading
T _{CHCTV}	Control Active Delay 2	3	31	3	22	ns	



CLOCK TIMINGS

 $T_C=-55^{\circ}C$ to $+125^{\circ}C,\,V_{CC}=5V\,\pm10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with $C_L=50$ pF. For AC tests, input $V_{IL}=0.45V$ and $V_{IH}=2.4V$ except at X1 where $V_{IH}=V_{CC}-0.5V.$

			Val	ues			
Symbol	Parameter	M80C186X	L	M80C186XL	.12	Unit	Test Conditions
		Min	Max	Min	Max		Containono
M80C186	XL CLKIN REQUIREMENT						
T _{CKIN}	CLKIN Period	50	∞	40	8	ns	
T _{CLCK}	CLKIN Low Time	20	∞	16	8	ns	1.5V ⁽²⁾
T _{CHCK}	CLKIN High Time	20	8	16	8	ns	1.5V ⁽²⁾
T _{CKHL}	CLKIN Fall Time		5		5	ns	3.5 to 1.0V
T _{CKLH}	CLKIN Rise Time		5		5	ns	1.0 to 3.5V
M80C186	XL CLKOUT TIMING						
T _{CICO}	CLKIN to CLKOUT Skew		25		21	ns	
T _{CLCL}	CLKOUT Period	100	8	80	8	ns	
T _{CLCH}	CLKOUT Low Time	0.5 T _{CLCL} - 6		0.5 T _{CLCL} — 5		ns	$C_L = 100 pF^{(3)}$
T _{CHCL}	CLKOUT High Time	0.5 T _{CLCL} — 6		0.5 T _{CLCL} — 5		ns	$C_L = 100 pF^{(4)}$
T _{CH1CH2}	CLKOUT Rise Time		10		10	ns	1.0 to 3.5V
T _{CL2CL1}	CLKOUT Fall Time		10		10	ns	3.5 to 1.0V

- 1. External clock applied to X1 and X2 not connected.
 2. T_{CLCK} and T_{CHCK} (CLKIN Low and High times) should not have a duration less than 40% of T_{CKIN}.
 3. Tested under worst case conditions: V_{CC} = 5.5V T_C = +125°C.
 4. Tested under worst case conditions: V_{CC} = 4.5V T_C = -55°C.



CLOCK TIMINGS

 $T_C = -55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with $C_L = 50$ pF. For AC tests, input $V_{IL} = 0.45\text{V}$ and $V_{IH} = 2.4\text{V}$ except at X1 where $V_{IH} = V_{CC} = 0.5\text{V}$.

			Val	ues			
Symbol	Parameter	M80C186XL	.16	M80C186XL	.20	Unit	Test Conditions
		Min	Max	Min	Max		Conditions
M80C186	XL CLKIN REQUIREMENT	'S(1)					
T _{CKIN}	CLKIN Period	31.25	∞	25	8	ns	
T _{CLCK}	CLKIN Low Time	13	∞	10	8	ns	1.5V ⁽²⁾
T _{CHCK}	CLKIN High Time	13	8	10	8	ns	1.5V ⁽²⁾
T _{CKHL}	CLKIN Fall Time		5		5	ns	3.5 to 1.0V
T _{CKLH}	CLKIN Rise Time		5		5	ns	1.0 to 3.5V
M80C186	XL CLKOUT TIMING						
T _{CICO}	CLKIN to CLKOUT Skew		17		17	ns	
T _{CLCL}	CLKOUT Period	62.5		50		ns	
T _{CLCH}	CLKOUT Low Time	0.5 T _{CLCL} — 5		0.5 T _{CLCL} - 5		ns	$C_L = 100 pF^{(3)}$
T _{CHCL}	CLKOUT High Time	0.5 T _{CLCL} — 5		0.5 T _{CLCL} — 5		ns	$C_L = 100 pF^{(4)}$
T _{CH1CH2}	CLKOUT Rise Time		10		8	ns	1.0 to 3.5V
T _{CL2CL1}	CLKOUT Fall Time		10		8	ns	3.5 to 1.0V

- 1. External clock applied to X1 and X2 not connected.
 2. T_{CLCK} and T_{CHCK} (CLKIN Low and High times) should not have a duration less than 40% of T_{CKIN}.
 3. Tested under worst case conditions: V_{CC} = 5.5V. T_C = +125°C.
 4. Tested under worst case conditions: V_{CC} = 4.5V. T_C = -55°C.



READY, PERIPHERAL AND QUEUE STATUS TIMINGS

 $T_C=-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$, $V_{CC}=5\text{V}\pm10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with $C_L=50$ pF. For AC tests, input $V_{IL}=0.45\text{V}$ and $V_{IH}=2.4\text{V}$ except at X1 where $V_{IH}=V_{CC}-0.5\text{V}$.

			Val	ues			
Symbol	Parameter	M80C	186XL	M80C1	86XL12	Unit	Test Conditions
		Min	Max	Min	Max		
M80C186X	(L READY AND PERIPHERAL TI	ed More T	han On	ce)			
T _{SRYCL}	Synchronous Ready (SRDY) Transition Setup Time ⁽¹⁾	15		15		ns	
T _{CLSRY}	SRDY Transition Hold Time ⁽¹⁾	15		15		ns	
T _{ARYCH}	ARDY Resolution Transition Setup Time ⁽²⁾	15		15		ns	
T _{CLARX}	ARDY Active Hold Time(1)	15		15		ns	
T _{ARYCHL}	ARDY Inactive Holding Time	15		15		ns	
T _{ARYLCL}	Asynchronous Ready (ARDY) Setup Time ⁽¹⁾	25		25		ns	
T _{INVCH}	INTx, NMI, TEST/BUSY, TMR IN Setup Time ⁽²⁾	15		15		ns	
T _{INVCL}	DRQ0, DRQ1 Setup Time(2)	15		15		ns	
M80C186X	(L PERIPHERAL AND QUEUE S	TATUS TI	MING RES	PONSES			
T _{CLTMV}	Timer Output Delay		40		33	ns	
T _{CHQSV}	Queue Status Delay		37		32	ns	

NOTES:

To guarantee proper operation.
 To guarantee recognition at clock edge.



READY, PERIPHERAL, AND QUEUE STATUS TIMINGS

 $T_C=-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$, $V_{CC}=5\text{V}\pm10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with $C_L=50$ pF. For AC tests, input $V_{IL}=0.45\text{V}$ and $V_{IH}=2.4\text{V}$ except at X1 where $V_{IH}=V_{CC}-0.5\text{V}$.

			Val	ues			
Symbol	Parameter	M80C1	86XL16	M80C1	86XL20	Unit	Test Conditions
		Min	Max	Min	Max		
M80C186X	(L READY AND PERIPHERAL TI						
T _{SRYCL}	Synchronous Ready (SRDY) Transition Setup Time ⁽¹⁾	15		10		ns	
T _{CLSRY}	SRDY Transition Hold Time ⁽¹⁾	15		10		ns	
T _{ARYCH}	ARDY Resolution Transition Setup Time ⁽²⁾	15		10		ns	
T _{CLARX}	ARDY Active Hold Time(1)	15		10		ns	
T _{ARYCHL}	ARDY Inactive Holding Time	15		10		ns	
T _{ARYLCL}	Asynchronous Ready (ARDY) Setup Time ⁽¹⁾	25		15		ns	
T _{INVCH}	INTx, NMI, TEST/BUSY, TMR IN Setup Time ⁽²⁾	15		10		ns	
T _{INVCL}	DRQ0, DRQ1 Setup Time(2)	15		10		ns	
M80C186X	(L PERIPHERAL AND QUEUE S	TATUS TI	MING RES	PONSES			
T _{CLTMV}	Timer Output Delay		27		22	ns	
T _{CHQSV}	Queue Status Delay		30		27	ns	

NOTES:

- To guarantee proper operation.
 To guarantee recognition at clock edge.



RESET AND HOLD/HLDA TIMINGS

 $T_C=-55^{\circ}C$ to $+125^{\circ}C,~V_{CC}=5V~\pm10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with $C_L=50$ pF. For AC tests, input $V_{IL}=0.45V$ and $V_{IH}=2.4V$ except at X1 where $V_{IH}=V_{CC}-0.5V.$

			Val	ues							
Symbol	Parameter	M80C	186XL	M80C186XL12		Unit	Test Conditions				
		Min	Max	Min	Max						
M80C186	M80C186XL RESET AND HOLD/HLDA TIMING REQUIREMENTS										
T _{RESIN}	RES Setup	15		15		ns					
T _{HVCL}	HOLD Setup(1)	15		15		ns					
M80C186	XL GENERAL TIMING RESPO	NSES (List	ed More T	han Once)							
T _{CLAZ}	Address Float Delay	T _{CLAX}	30	T _{CLAX}	25	ns					
T_{CLAV}	Address Valid Delay	3	44	3	36	ns					
M80C186	XL RESET AND HOLD/HLDA	TIMING RE	SPONSES								
T _{CLRO}	Reset Delay		40		33	ns					
T _{CLHAV}	HLDA Valid Delay	3	40	3	33	ns					
T _{CHCZ}	Command Lines Float Delay		40		33	ns					
T _{CHCV}	Command Lines Valid Delay (after Float)		44		36	ns					

^{1.} To guarantee recognition at next clock.



RESET AND HOLD/HLDA TIMINGS

 $T_C=-55^{\circ}C$ to $+125^{\circ}C,~V_{CC}=5V~\pm10\%$ All timings are measured at 1.5V and 100 pF loading on CLKOUT unless otherwise noted. All output test conditions are with $C_L=50$ pF. For AC tests, input $V_{IL}=0.45V$ and $V_{IH}=2.4V$ except at X1 where $V_{IH}=V_{CC}-0.5V.$

			Val	ues							
Symbol	Parameter	M80C1	86XL16	M80C186XL20		Unit	Test Conditions				
		Min	Max	Min	Max						
M80C186	M80C186XL RESET AND HOLD/HLDA TIMING REQUIREMENTS										
T _{RESIN}	RES Setup	15		15		ns					
T _{HVCL}	HOLD Setup(1)	15		10		ns					
M80C186	XL GENERAL TIMING RESPO	NSES (List	ed More T	han Once)							
T _{CLAZ}	Address Float Delay	T _{CLAX}	20	T _{CLAX}	20	ns					
T_{CLAV}	Address Valid Delay	1	33	1	22	ns					
M80C186	XL RESET AND HOLD/HLDA	TIMING RE	SPONSES								
T _{CLRO}	Reset Delay		27		22	ns					
T _{CLHAV}	HLDA Valid Delay	1	25	1	22	ns					
T _{CHCZ}	Command Lines Float Delay		28		25	ns					
T _{CHCV}	Command Lines Valid Delay (after Float)		32		26	ns					

NOTE:

^{1.} To guarantee recognition at next clock.



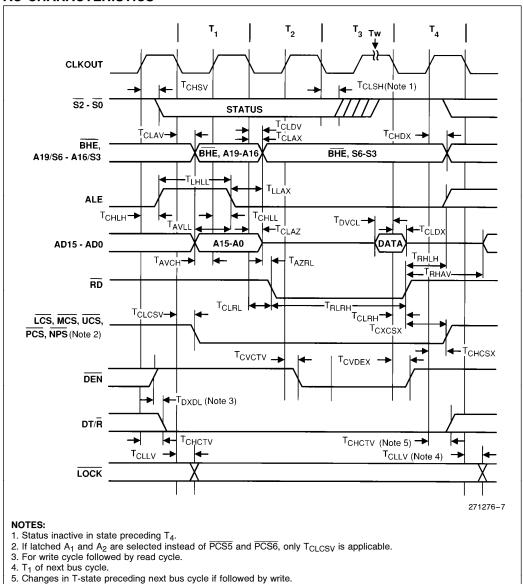
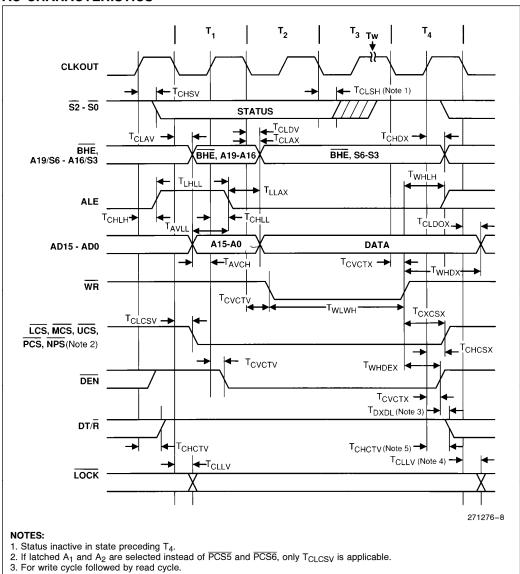


Figure 5. Read Cycle Waveforms



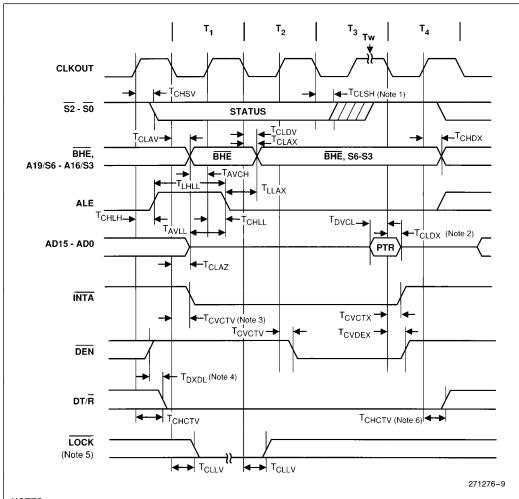


- 4. T₁ of next bus cycle.

 5. Changes in T-state preceding next bus cycle if followed by read, INTA, or halt.

Figure 6. Write Cycle Waveforms





- Status inactive in state preceding T₄.
 The data hold time lasts only until INTA goes inactive, even if the INTA transition occurs prior to T_{CLDX} (min).
- 3. INTA occurs one clock later in Slave Mode.
- 4. For write cycle followed by interrupt acknowledge cycle.
- 5. LOCK is active upon T₁ of the first interrupt acknowledge cycle and inactive upon T₂ of the second interrupt acknowledge
- 6. Changes in T-state preceding next bus cycle if followed by write.

Figure 7. Interrupt Acknowledge Cycle Waveforms



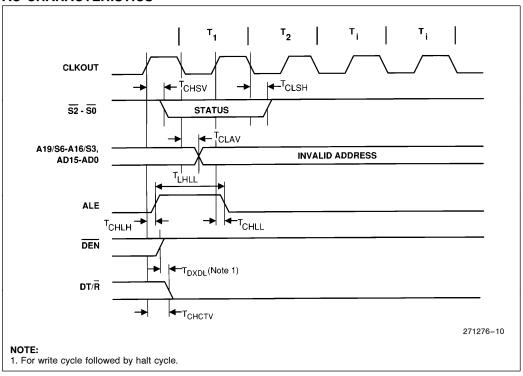


Figure 8. Software Halt Cycle Waveforms



WAVEFORMS

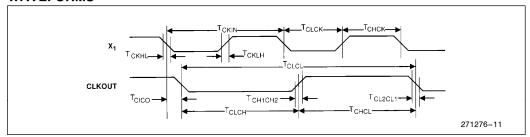


Figure 9. Clock Waveforms

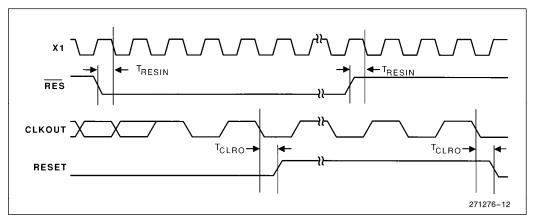


Figure 10. Reset Waveforms

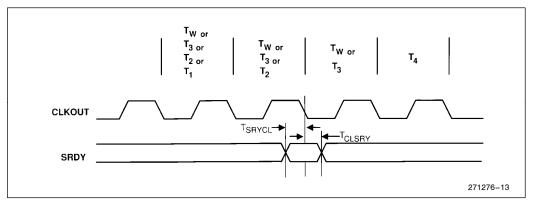


Figure 11. Synchronous Ready (SRDY) Waveforms



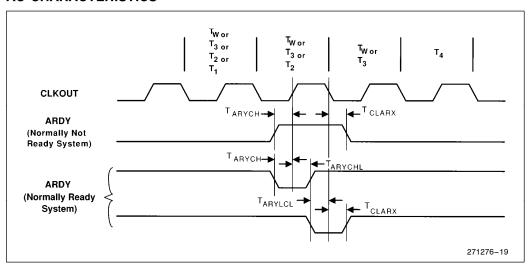


Figure 12. Asynchronous Ready (ARDY) Waveforms

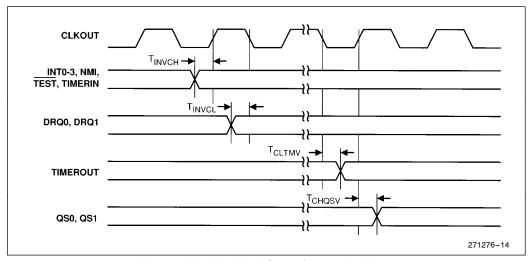


Figure 13. Peripheral and Queue Status Waveforms



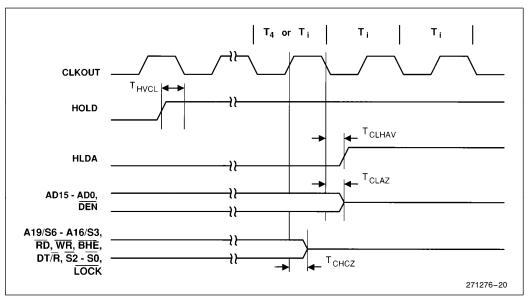


Figure 14. HOLD/HLDA Waveforms (Entering Hold)

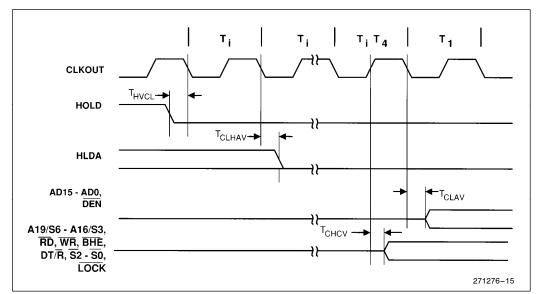


Figure 15. HOLD/HLDA Waveforms (Leaving Hold)



EXPLANATION OF THE AC SYMBOLS

Each timing symbol has from 5 to 7 characters. The first character is always a 'T' (stands for time). The other characters, depending on their positions, stand for the name of a signal or the logical status of that signal. The following is a list of all the characters and what they stand for.

A: Address

ARY: Asynchronous Ready Input

C: Clock Output

CK: Clock Input

CS: Chip Select

CT: Control (DT/ \overline{R} , \overline{DEN} , ...)

D: Data Input

DE: DEN

H: Logic Level High

OUT: Input (DRQ0, TIM0, ...)

L: Logic Level Low or ALE

O: Output

QS: Queue Status (QS1, QS2)
R: RD Signal, RESET Signal

S: Status ($\overline{S0}$, $\overline{S1}$, $\overline{S2}$)

SRY: Synchronous Ready Input

V: Valid

W: WR Signal

X: No Longer a Valid Logic Level

Z: Float

Examples:

T_{CLAV} — Time from Clock low to Address valid

T_{CHLH} — Time from Clock high to ALE high

T_{CLCSV} — Time from Clock low to Chip Select valid



DERATING CURVES

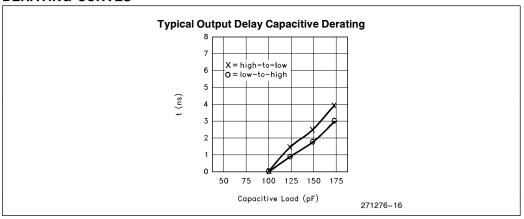


Figure 16. Capacitive Derating Curve

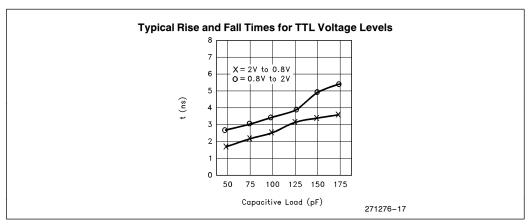


Figure 17. TTL Level Rise and Fall Times for Output Buffers

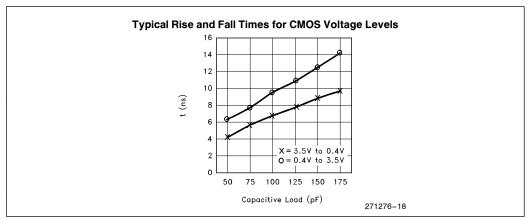


Figure 18. CMOS Level Rise and Fall Times for Output Buffers



M80C186XL EXECUTION TIMINGS

A determination of M80C186XL program execution timing must consider the bus cycles necessary to prefetch instructions as well as the number of execution unit cycles necessary to execute instructions. The following instruction timings represent the minimum execution time in clock cycles for each instruction. The timings given are based on the following assumptions:

- The opcode, along with any data or displacement required for execution of a particular instruction, has been prefetched and resides in the queue at the time it is needed.
- No wait states or bus HOLDs occur.
- All word-data is located on even-address boundaries

All jumps and calls include the time required to fetch the opcode of the next instruction at the destination address.

All instructions which involve memory accesses can require one or two additional clocks above the minimum timings shown due to the asynchronous handshake between the bus interface unit (BIU) and execution unit.

With a 16-bit BIU, the M80C186XL has sufficient bus performance to ensure that an adequate number of prefetched bytes will reside in the queue most of the time. Therefore, actual program execution time will not be substantially greater than that derived from adding the instruction timings shown.



INSTRUCTION SET SUMMARY

Function		Fo	rmat		Clock Cycles	Comments
DATA TRANSFER MOV = Move:						
Register to Register/Memory	1000100w	mod reg r/m			2/12	
Register/memory to register	1000101w	mod reg r/m			2/9	
Immediate to register/memory	1100011w	mod 000 r/m	data	data if w=1	12-13	8/16-bit
Immediate to register	1011w reg	data	data if w = 1		3-4	8/16-bit
Memory to accumulator	1010000w	addr-low	addr-high		8	
Accumulator to memory	1010001w	addr-low	addr-high		9	
Register/memory to segment register	10001110	mod 0 reg r/m			2/9	
Segment register to register/memory	10001100	mod 0 reg r/m			2/11	
PUSH = Push:						
Memory	11111111	mod 1 1 0 r/m			16	
Register	01010 reg				10	
Segment register	0 0 0 reg 1 1 0]			9	
Immediate	011010s0	data	data if s = 0		10	
PUSHA = Push All	01100000				36	
POP = Pop:		,				
Memory	10001111	mod 0 0 0 r/m			20	
Register	01011 reg				10	
Segment register	0 0 0 reg 1 1 1	(reg≠01)			8	
POPA = Pop All	01100001				51	
XCHG = Exchange:						
Register/memory with register	1000011w	mod reg r/m			4/17	
Register with accumulator	10010 reg				3	
IN = Input from:						
Fixed port	1110010w	port			10	
Variable port	1110110w				8	
OUT = Output to:		I				
Fixed port	1110011w	port			9	
Variable port	1110111w				7	
XLAT = Translate byte to AL	11010111				11	
LEA = Load EA to register	10001101	mod reg r/m			6	
LDS = Load pointer to DS	11000101	mod reg r/m	(mod≠11)		18	
LES = Load pointer to ES	11000100	mod reg r/m	(mod≠11)		18	
LAHF = Load AH with flags	10011111]			2	
SAHF = Store AH into flags	10011110]			3	
PUSHF = Push flags	10011100]			9	
POPF = Pop flags	10011101]			8	



Function		Fo	rmat		Clock Cycles	Comments
DATA TRANSFER (Continued) SEGMENT = Segment Override:						
cs	00101110				2	
SS	00110110]			2	
DS	00111110	ĺ			2	
ES	00100110]			2	•
ARITHMETIC	00100110	J				
ADD = Add:		,				
Reg/memory with register to either	00000dw	mod reg r/m			3/10	
Immediate to register/memory	100000sw	mod 0 0 0 r/m	data	data if s w = 01	4/16	
Immediate to accumulator	0000010w	data	data if $w = 1$		3/4	8/16-bit
ADC = Add with carry:						
Reg/memory with register to either	000100dw	mod reg r/m			3/10	
Immediate to register/memory	100000sw	mod 0 1 0 r/m	data	data if s w = 01	4/16	
Immediate to accumulator	0001010w	data	data if w = 1		3/4	8/16-bit
INC = Increment:						
Register/memory	1111111w	mod 0 0 0 r/m			3/15	
Register	0 1 0 0 0 reg]			3	
SUB = Subtract:						
Reg/memory and register to either	001010dw	mod reg r/m			3/10	
Immediate from register/memory	100000sw	mod 1 0 1 r/m	data	data if s w=01	4/16	
Immediate from accumulator	0010110w	data	data if w = 1]	3/4	8/16-bit
SBB = Subtract with borrow:				•		
Reg/memory and register to either	000110dw	mod reg r/m			3/10	
Immediate from register/memory	100000sw	mod 0 1 1 r/m	data	data if s w = 01	4/16	
Immediate from accumulator	0001110w	data	data if w = 1]	3/4	8/16-bit
DEC = Decrement				ļ		
Register/memory	1111111w	mod 0 0 1 r/m			3/15	
Register	01001 reg]			3	
CMP = Compare:						
Register/memory with register	0011101w	mod reg r/m			3/10	
Register with register/memory	0011100w	mod reg r/m			3/10	
Immediate with register/memory	100000sw	mod 1 1 1 r/m	data	data if s w=01	3/10	•
Immediate with accumulator	0011110w	data	data if w = 1]	3/4	8/16-bit
NEG = Change sign register/memory	1111011w	mod 0 1 1 r/m		•	3/10	
AAA = ASCII adjust for add	00110111	j			8	
DAA = Decimal adjust for add	00100111	ĺ			4	
AAS = ASCII adjust for subtract	00111111	j			7	
DAS = Decimal adjust for subtract	00101111	j			4	
MUL = Multiply (unsigned):	1111011w	mod 100 r/m			4	
Register-Byte	LITTOTIW	11100 100 17111			26-28	
Register-Word					35-37	
Memory-Byte Memory-Word					32-34 41-43	
Memory-word Shaded areas indicate instructions		0000 (0000			41-43	L



Function		Clock Cycles	Comments			
ARITHMETIC (Continued)						
IMUL = Integer multiply (signed):	1111011w	mod 1 0 1 r/m				
Register-Byte Register-Word Memory-Byte Memory-Word					25-28 34-37 31-34 40-43	
IMUL = Integer Immediate multiply (signed)	011010s1	mod reg r/m	data	data if s=0	22-25/ 29-32	
DIV = Divide (unsigned):	1111011w	mod 1 1 0 r/m				
Register-Byte Register-Word Memory-Byte Memory-Word					29 38 35 44	
IDIV = Integer divide (signed):	1111011w	mod 1 1 1 r/m				
Register-Byte Register-Word Memory-Byte Memory-Word					44-52 53-61 50-58 59-67	
AAM = ASCII adjust for multiply	11010100	00001010			19	
AAD = ASCII adjust for divide	11010101	00001010			15	
CBW = Convert byte to word	10011000				2	
CWD = Convert word to double word	10011001				4	
LOGIC Shift/Rotate Instructions:						
Register/Memory by 1	1101000w	mod TTT r/m			2/15	
Register/Memory by CL	1101001w	mod TTT r/m			5+n/17+n	
Register/Memory by Count	1100000w	mod TTT r/m	count		5+n/17+n	
AND = And:		TTT Instruction 0 0 0				
Reg/memory and register to either	001000dw	mod reg r/m			3/10	
Immediate to register/memory	1000000w	mod 1 0 0 r/m	data	data if w = 1	4/16	
Immediate to accumulator	0010010w	data	data if w=1		3/4	8/16-bit
TEST = And function to flags, no resu	ilt:					
Register/memory and register	1000010w	mod reg r/m			3/10	
Immediate data and register/memory	1111011w	mod 0 0 0 r/m	data	data if w = 1	4/10	
Immediate data and accumulator	1010100w	data	data if w=1		3/4	8/16-bit
OR = Or:						
Reg/memory and register to either	000010dw	mod reg r/m			3/10	
Immediate to register/memory	1000000w	mod 0 0 1 r/m	data	data if w = 1	4/16	
Immediate to accumulator	0000110w	data	data if w=1		3/4	8/16-bit



Function		Fo	rmat		Clock Cycles	Comments
LOGIC (Continued) XOR = Exclusive or:						
Reg/memory and register to either	001100dw	mod reg r/m			3/10	
Immediate to register/memory	1000000w	mod 1 1 0 r/m	data	data if w=1	4/16	
Immediate to accumulator	0011010w	data	data if w=1		3/4	8/16-bit
NOT = Invert register/memory	1111011w	mod 0 1 0 r/m			3/10	
STRING MANIPULATION		1				
MOVS = Move byte/word	1010010w				14	
CMPS = Compare byte/word	1010011w				22	
SCAS = Scan byte/word	1010111w				15	
LODS = Load byte/wd to AL/AX	1010110w				12	
STOS = Store byte/wd from AL/AX	1010101w				10	
INS = Input byte/wd from DX port	0110110w				14	
OUTS = Output byte/wd to DX port	0110111w				14	
Repeated by count in CX (REP/REPE/F	REPZ/REPNE/REP	NZ)				
MOVS = Move string	11110010	1010010w			8+8n	
CMPS = Compare string	1111001z	1010011w			5 + 22n	
SCAS = Scan string	1111001z	1010111w			5 + 15n	
LODS = Load string	11110010	1010110w			6+11n	
STOS = Store string	11110010	1010101w			6+9n	
INS = Input string	11110010	0110110w			8+8n	
OUTS = Output string	11110010	0110111w			8+8n	
CONTROL TRANSFER						
CALL = Call:						
Direct within segment	11101000	disp-low	disp-high		15	
Register/memory indirect within segment	11111111	mod 0 1 0 r/m			13/19	
	10011010	acamor	at officet		23	
Direct intersegment	10011010	segmer			23	
		segment	selector			
Indirect intersegment	11111111	mod 0 1 1 r/m	(mod ≠ 11)		38	
JMP = Unconditional jump:						
Short/long	11101011	disp-low			14	
Direct within segment	11101001	disp-low	disp-high		14	
Register/memory indirect within segment	11111111	mod 1 0 0 r/m			11/17	
Direct intersegment	11101010	segmer	nt offset		14	
		segment	selector			
Indirect intersegment	11111111	mod 1 0 1 r/m	(mod ≠ 11)		26	
Shadad areas indicate instruction		9096/9099 mio	-			



Function		Format		Clock Cycles	Comments
CONTROL TRANSFER (Continued) RET = Return from CALL:					
Within segment	11000011			16	
Within seg adding immed to SP	11000010	data-low	data-high	18	
Intersegment	11001011			22	
Intersegment adding immediate to SP	11001010	data-low	data-high	25	
JE/JZ = Jump on equal/zero	01110100	disp		4/13	JMP not
JL/JNGE = Jump on less/not greater or equal	01111100	disp		4/13	taken/JMP
JLE/JNG = Jump on less or equal/not greater	01111110	disp		4/13	taken
JB/JNAE = Jump on below/not above or equal	01110010	disp		4/13	
JBE/JNA = Jump on below or equal/not above	01110110	disp		4/13	
JP/JPE = Jump on parity/parity even	01111010	disp		4/13	
JO = Jump on overflow	01110000	disp		4/13	
JS = Jump on sign	01111000	disp		4/13	
JNE/JNZ = Jump on not equal/not zero	01110101	disp		4/13	
JNL/JGE = Jump on not less/greater or equal	01111101	disp		4/13	
JNLE/JG = Jump on not less or equal/greater	01111111	disp		4/13	
JNB/JAE = Jump on not below/above or equal	01110011	disp		4/13	
JNBE/JA = Jump on not below or equal/above	01110111	disp		4/13	
JNP/JPO = Jump on not par/par odd	01111011	disp		4/13	
JNO = Jump on not overflow	01110001	disp		4/13	
JNS = Jump on not sign	01111001	disp		4/13	
JCXZ = Jump on CX zero	11100011	disp		5/15	
LOOP = Loop CX times	11100010	disp		6/16	LOOP not
LOOPZ/LOOPE = Loop while zero/equal	11100001	disp		6/16	taken/LOOP taken
LOOPNZ/LOOPNE = Loop while not zero/equal	11100000	disp		6/16	tanon
ENTER = Enter Procedure	11001000	data-low	data-high L		
L = 0				15	
L = 1 L > 1				25 22+16(n-1)	
LEAVE = Leave Procedure	11001001			8	
INT = Interrupt:					
Type specified	11001101	type		47	
Type 3	11001100			45	if INT. taken/ if INT. not
INTO = Interrupt on overflow	11001110			48/4	taken
IRET = Interrupt return	11001111			28	
BOUND = Detect value out of range	01100010	mod reg r/m		33-35	



Function	Format	Clock Cycles	Comments
PROCESSOR CONTROL			
CLC = Clear carry	11111000	2	
CMC = Complement carry	11110101	2	
STC = Set carry	11111001	2	
CLD = Clear direction	11111100	2	
STD = Set direction	11111101	2	
CLI = Clear interrupt	11111010	2	
STI = Set interrupt	11111011	2	
HLT = Halt	11110100	2	
WAIT = Wait	10011011	6	if TEST = 0
LOCK = Bus lock prefix	11110000	2	
NOP = No Operation	1001000	3	
	(TTT LLL are opcode to processor extension)		

Shaded areas indicate instructions not available in 8086/8088 microsystems.

FOOTNOTES

The Effective Address (EA) of the memory operand is computed according to the mod and r/m fields:

		according to the mod and min heraci
if mod	=	11 then r/m is treated as a REG field
if mod	=	00 then DISP = $0*$, disp-low and disp
		high are absent
if mod	=	01 then DISP = disp-low sign-ex-
		tended to 16-bits, disp-high is absent
if mod	=	10 then DISP = disp-high: disp-low
if r/m	=	000 then $EA = (BX) + (SI) + DISP$
if r/m	=	001 then $EA = (BX) + (DI) + DISP$
if r/m	=	010 then $EA = (BP) + (SI) + DISP$
if r/m	=	011 then $EA = (BP) + (DI) + DISP$
if r/m	=	100 then EA = (SI) + DISP
if r/m	=	101 then $EA = (DI) + DISP$
if r/m	=	110 then EA = (BP) $+$ DISP*
if r/m	=	111 then $EA = (BX) + DISP$

DISP follows 2nd byte of instruction (before data if required)

EA calculation time is 4 clock cycles for all modes, and is included in the execution times given whenever appropriate.

	in	accianad	according	+~	+ha	following
ıeu	15	assigned	according	ιO	uie	ioliowing.

	Segmen
reg	Registe
00	ES
01	CS
10	SS
11	DS

REG is assigned according to the following table:

16-Bit (w = 1)	8-Bit ($\mathbf{w} = 0$)
000 AX	000 AL
001 CX	001 CL
010 DX	010 DL
011 BX	011 BL
100 SP	100 AH
101 BP	101 CH
110 SI	110 DH
111 DI	111 BH

The physical addresses of all operands addressed by the BP register are computed using the SS segment register. The physical addresses of the destination operands of the string primitive operations (those addressed by the DI register) are computed using the ES segment, which may not be overridden.

Segment Override Prefix

0 0 1 r	eg 1	1	0
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^{*}except if mod = 00 and r/m = 110 then EA = disp-high: disp-low.